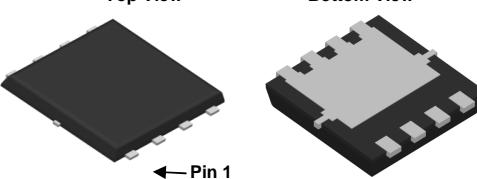
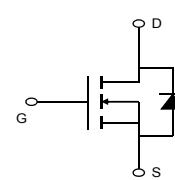


<p><b>28V N-Channel MOSFET</b></p> <p><b>PRODUCT SUMMARY</b></p> <p> <math>V_{DS}</math> (V) = 28V  <math>I_D</math> = 12A      (<math>V_{GS}</math> = 10V)  <math>R_{DS(ON)}</math> &lt; 9.9mΩ      (<math>V_{GS}</math> = 10V)  <math>R_{DS(ON)}</math> &lt; 14mΩ      (<math>V_{GS}</math> = 4.5V)         </p> <p>100% UIS Tested 100% <math>R_g</math> Tested</p> <ul style="list-style-type: none"> <li>• Trench Power αMOS Technology</li> <li>• Low <math>R_{DS(ON)}</math></li> <li>• Low Gate Charge</li> <li>• High Current Capability</li> <li>• RoHS and Halogen-Free Compliant</li> </ul> <p><b>Applications</b></p> <ul style="list-style-type: none"> <li>• DC/DC Converters in Computing</li> <li>• Isolated DC/DC Converters in Telecom and Industrial</li> </ul>	<p><b>DFN 3x3_EP</b></p> <p><b>Top View</b>      <b>Bottom View</b></p>  <p><b>Top View</b></p>  <p><b>Equivalent Circuit</b></p>  <p>Y :year code W :week code</p>
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### Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
36326	36326	PDFN3x3-8	Ø330mm	12mm	4000 units

Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted					
Parameter	Symbol	Maximum	Units		
Drain-Source Voltage	$V_{DS}$	28	V		
Gate-Source Voltage	$V_{GS}$	$\pm 12$	V		
Continuous Drain Current <sup>A</sup>	$I_D$	12	A		
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	36			
Continuous Drain Current <sup>A</sup>	$I_{DSM}$	12	A		
Avalanche Current <sup>C</sup>	$I_{AR}$	10	A		
Repetitive avalanche energy $L=0.1\text{mH}$ <sup>C</sup>	$E_{AR}$	7	mJ		
Power Dissipation <sup>B</sup>	$P_D$	19	W		
Power Dissipation <sup>A</sup>	$P_{DSM}$	3.1	W		
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C		

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	30	40	°C/W
Maximum Junction-to-Ambient <sup>A</sup>		60	75	°C/W
Maximum Junction-to-Case <sup>B</sup>	$R_{\theta JC}$	4.5	5.4	°C/W



SHENZHEN TUOFENG SEMICONDUCTOR TECHNOLOGY CO.,LTD

N-Channel Enhancement Mode Power MOSFET

36326

Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	28			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=25\text{V}, V_{GS}=0\text{V}$			1	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 12\text{V}$			100	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	0.50	0.85	1.20	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	80			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=12\text{A}$		8.5	9.9	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=10\text{A}$		10	14	$\text{m}\Omega$
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=12\text{A}$		45		S
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.7	1	V
$I_S$	Maximum Body-Diode Continuous Current				12	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		688		pF
$C_{\text{oss}}$	Output Capacitance			305		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			24		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	0.8	1.6	2.4	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=12\text{A}$		12		nC
$Q_g(4.5\text{V})$	Total Gate Charge			5.5		nC
$Q_{\text{gs}}$	Gate Source Charge			1.2		nC
$Q_{\text{gd}}$	Gate Drain Charge			1.3		nC
$t_{\text{D(on)}}$	Turn-On DelayTime	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=1.25\Omega, R_{\text{GEN}}=3\Omega$		3.5		ns
$t_r$	Turn-On Rise Time			3.0		ns
$t_{\text{D(off)}}$	Turn-Off DelayTime			15		ns
$t_f$	Turn-Off Fall Time			3.0		ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=12\text{A}, dl/dt=500\text{A}/\mu\text{s}$	5.6	7	8	ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=12\text{A}, dl/dt=500\text{A}/\mu\text{s}$	6.4	8	9.6	nC

A. The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$ . The Power dissipation  $P_{\text{DSM}}$  is based on  $R_{\theta JA}$   $t \leq 10\text{s}$  value and the maximum allowed junction temperature of  $150^\circ\text{C}$ . The value in any given application depends on the user's specific board design, and the maximum temperature of  $150^\circ\text{C}$  may be used if the PCB allows it.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=150^\circ\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ .

D. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to case  $R_{\theta JC}$  and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300 $\mu\text{s}$  pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{C}$ .

G. The maximum current rating is limited by bond-wires.

H. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

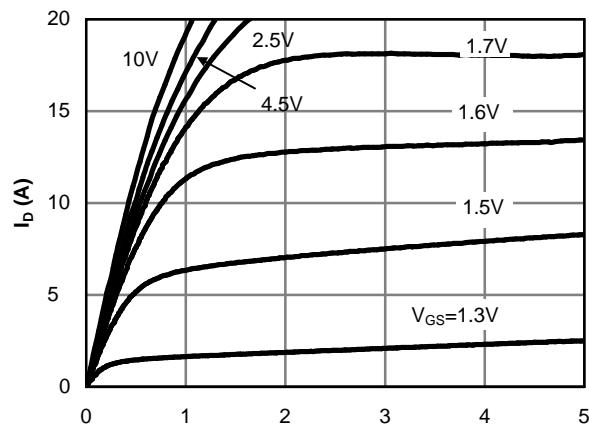


Fig 1: On-Region Characteristics

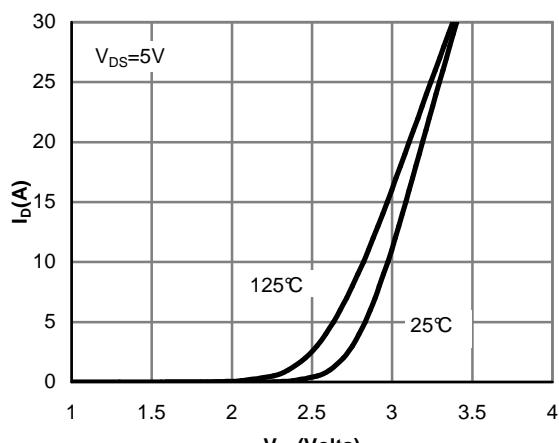


Figure 2: Transfer Characteristics

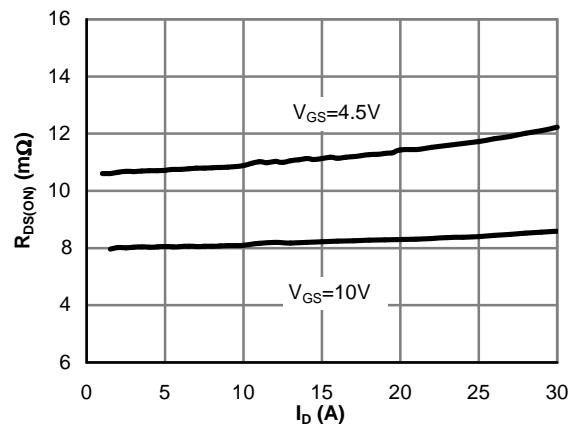


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

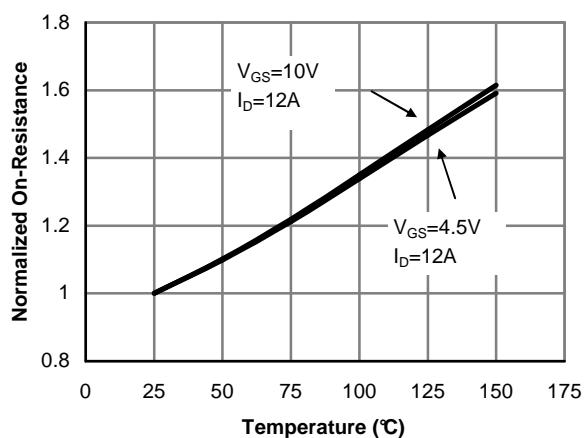


Figure 4: On-Resistance vs. Junction Temperature

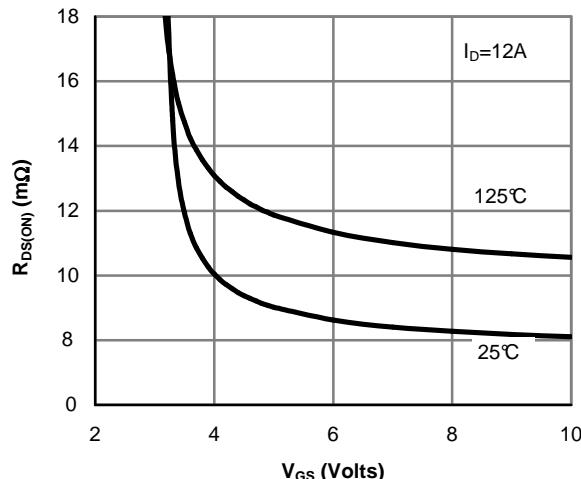


Figure 5: On-Resistance vs. Gate-Source Voltage

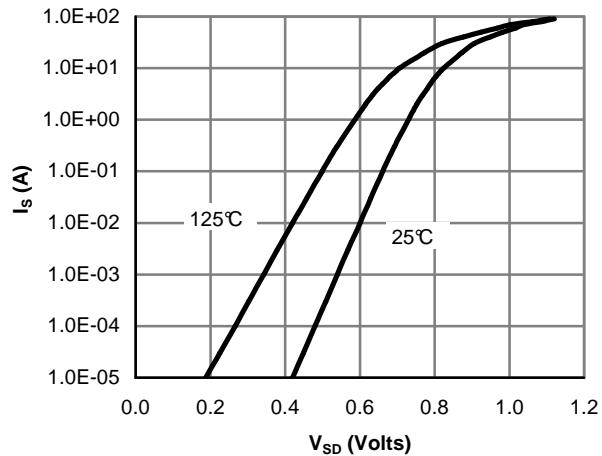
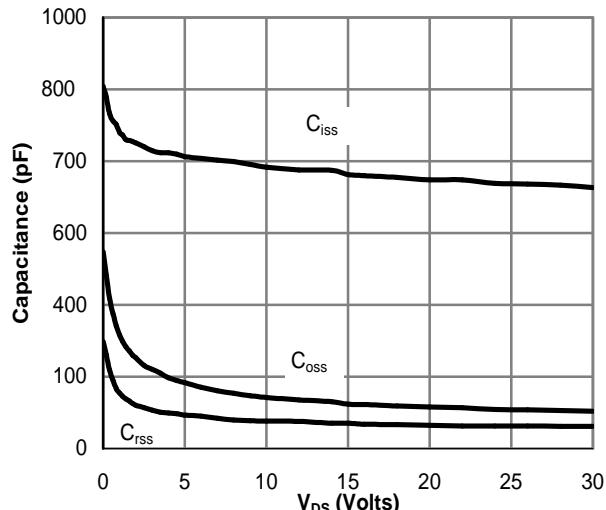
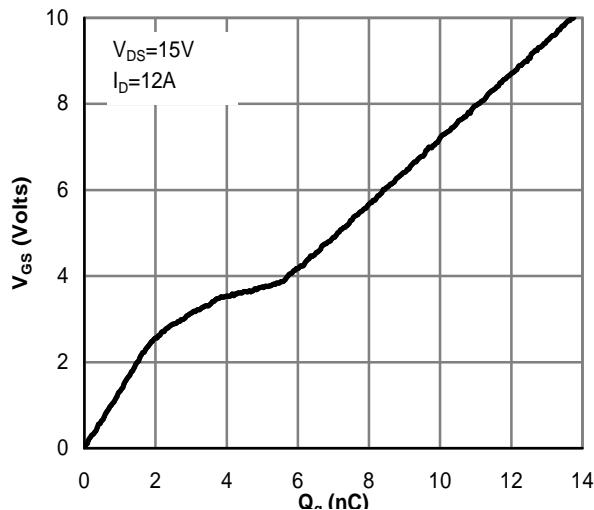
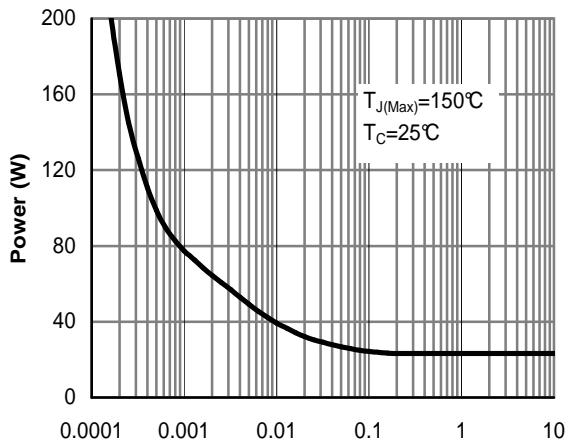
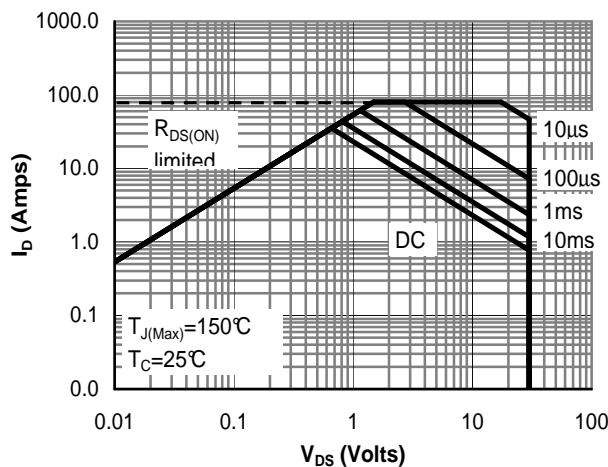
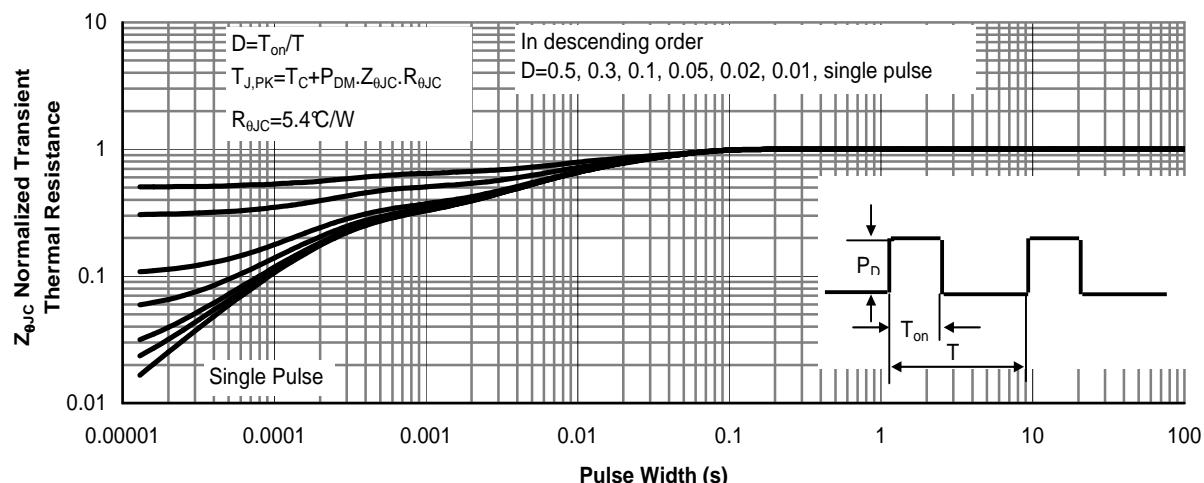


Figure 6: Body-Diode Characteristics

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Figure 8: Capacitance Characteristics**

**Figure 9: Maximum Forward Biased Safe Operating Area (Note F)**

**Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)**

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

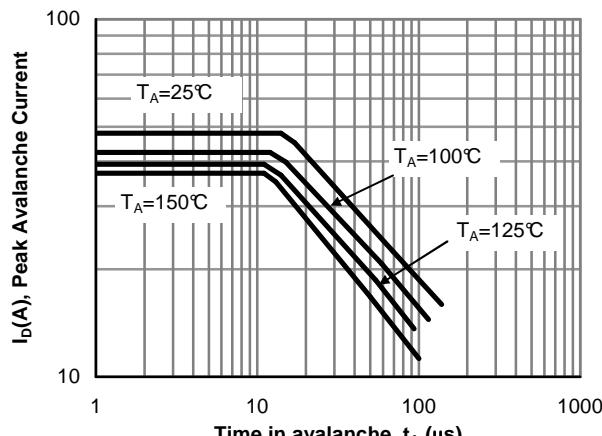


Figure 12: Single Pulse Avalanche capability  
(Note C)

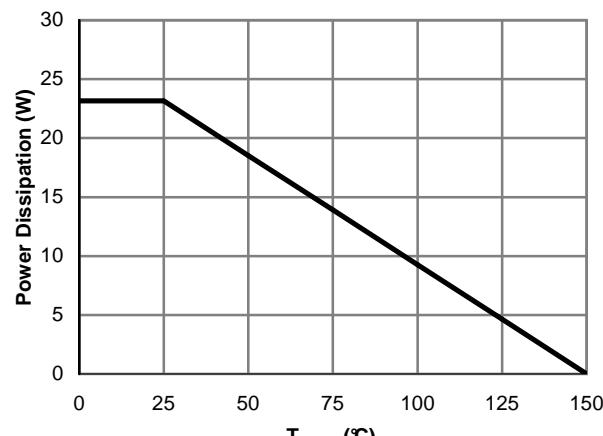


Figure 13: Power De-rating (Note F)

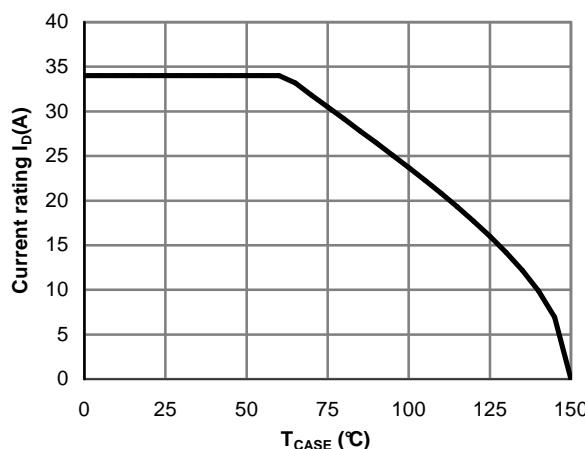


Figure 14: Current De-rating (Note F)

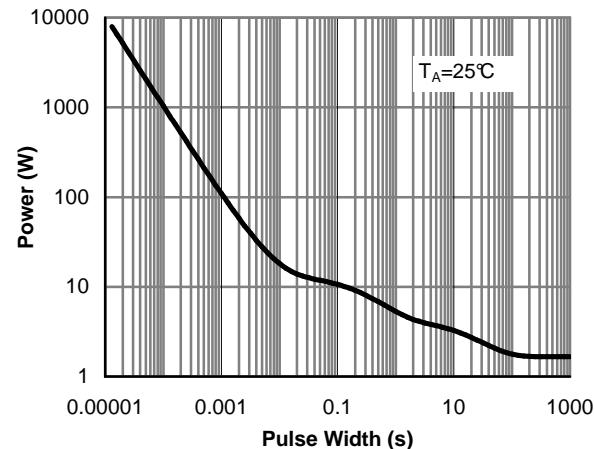


Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note H)

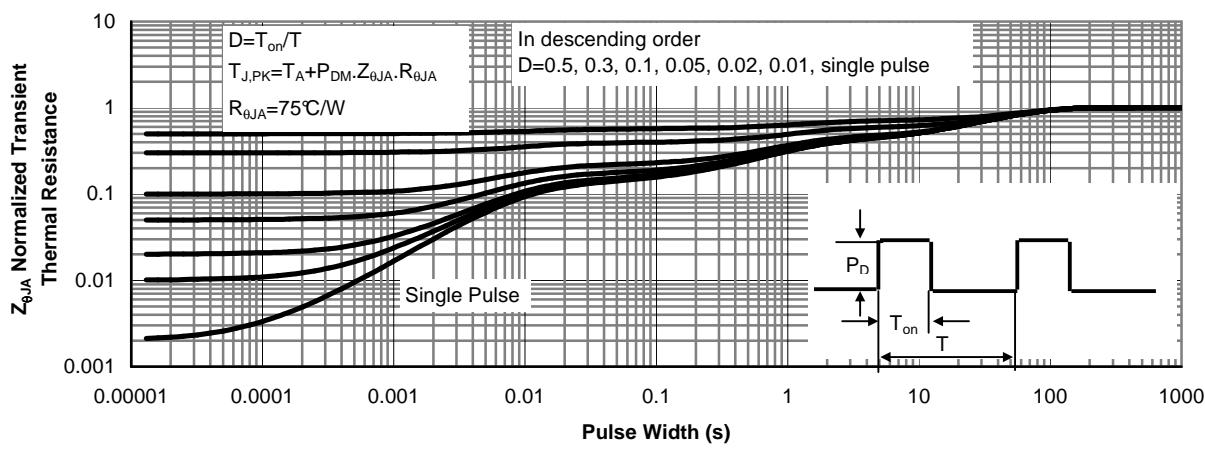
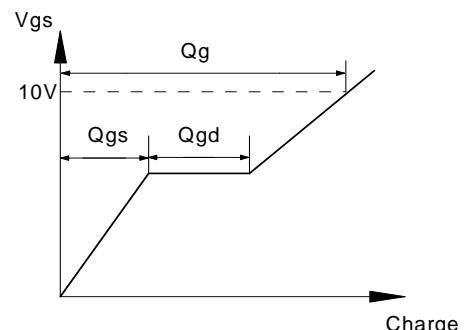
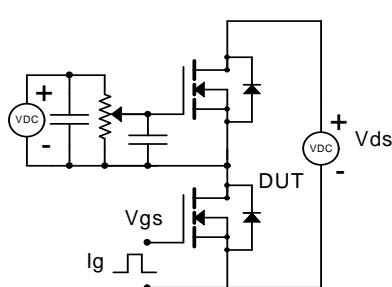
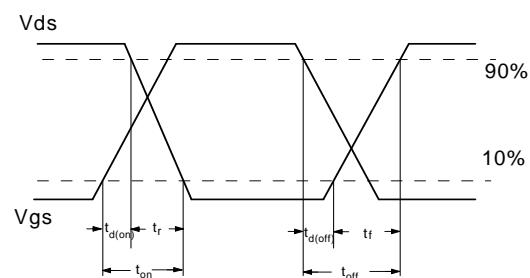
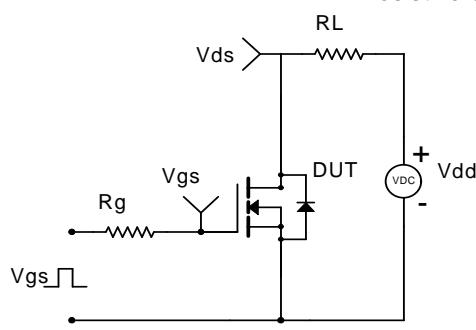


Figure 16: Normalized Maximum Transient Thermal Impedance (Note H)

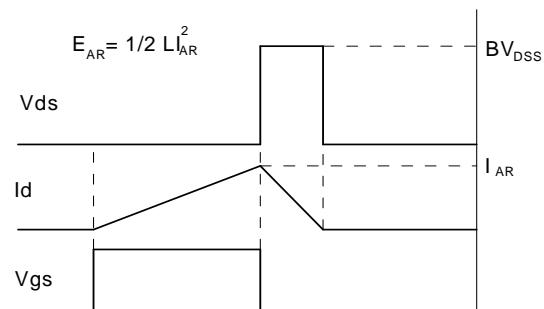
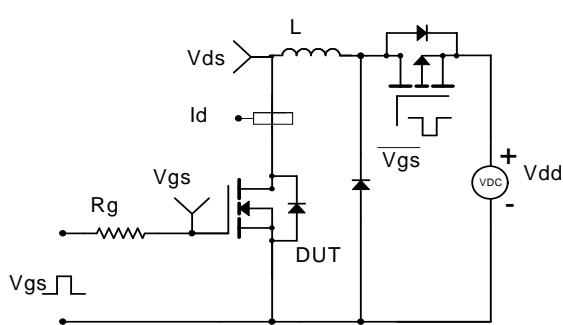
Gate Charge Test Circuit & Waveform



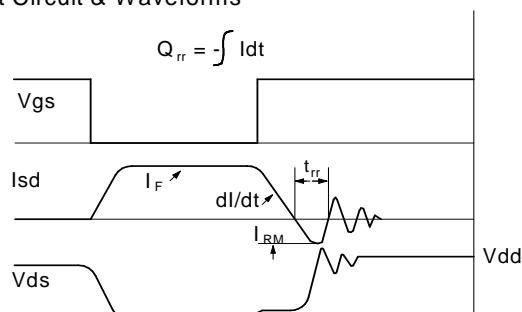
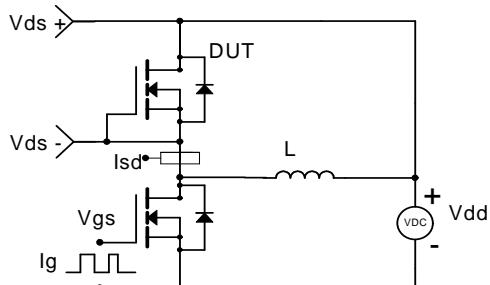
Resistive Switching Test Circuit & Waveforms



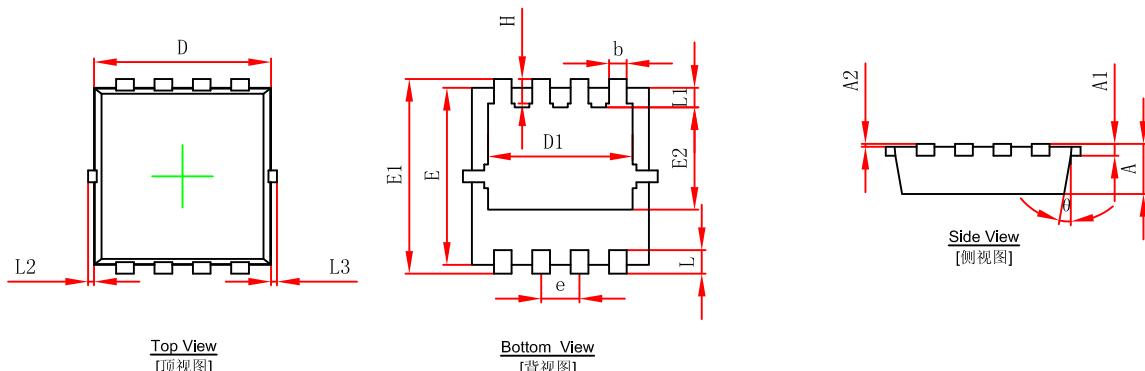
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

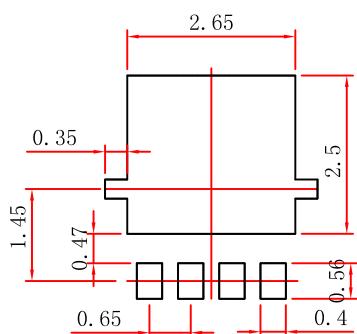


### PDFNWB3.3x3.3-8L Package Outline Dimensions



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.650	0.850	0.026	0.033
A1	0.152 REF.		0.006 REF.	
A2	0~0.05		0~0.002	
D	2.900	3.100	0.114	0.122
D1	2.300	2.600	0.091	0.102
E	2.900	3.100	0.114	0.122
E1	3.150	3.450	0.124	0.136
E2	1.535	1.935	0.060	0.076
b	0.200	0.400	0.008	0.016
e	0.550	0.750	0.022	0.030
L	0.300	0.500	0.012	0.020
L1	0.180	0.480	0.007	0.019
L2	0~0.100		0~0.004	
L3	0~0.100		0~0.004	
H	0.315	0.515	0.012	0.020
$\theta$	9°	13°	9°	13°

### PDFNWB3.3x3.3-8L Suggested Pad Layout



Note:

1. Controlling dimension: in millimeters.
2. General tolerance:  $\pm 0.05\text{mm}$ .
3. The pad layout is for reference purposes only.